

Supplementary Information

Evidence of Band Bending Induced by Hole Trapping at MAPbI₃ Perovskite/Metal Interface

Y.-F. Chen, Y.-T. Tsai, D. M. Bassani, R. Clerc*, D. Forgács, H. J. Bolink, M. Wussler, W. Jaegermann, G. Wantz, and L. Hirsch*

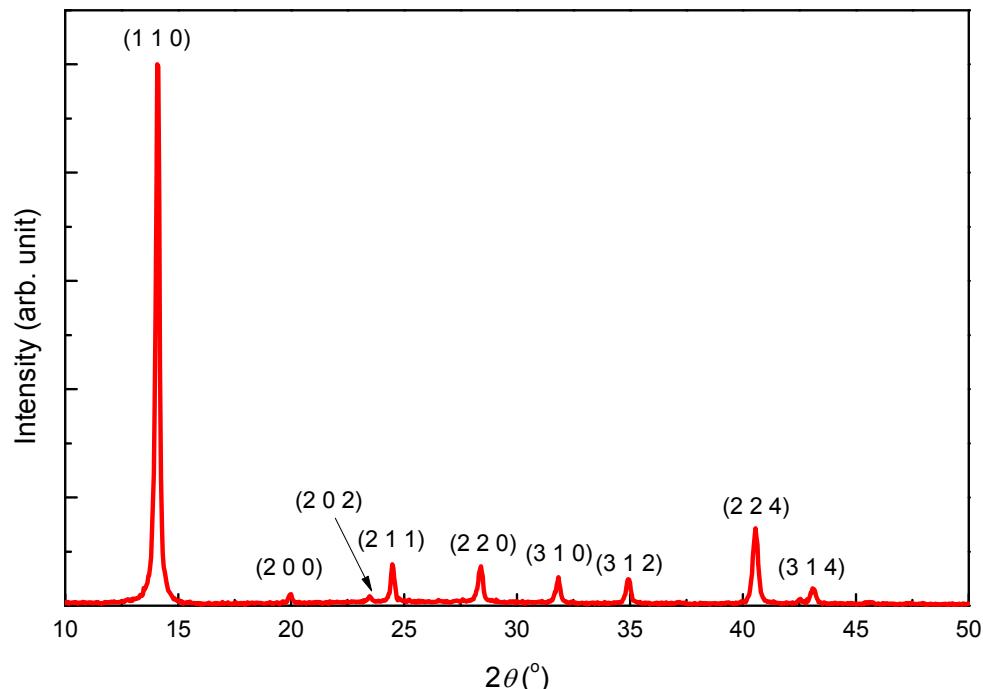


Figure S1. X-ray diffraction spectrum of a 200-nm-thick MAPbI₃ film

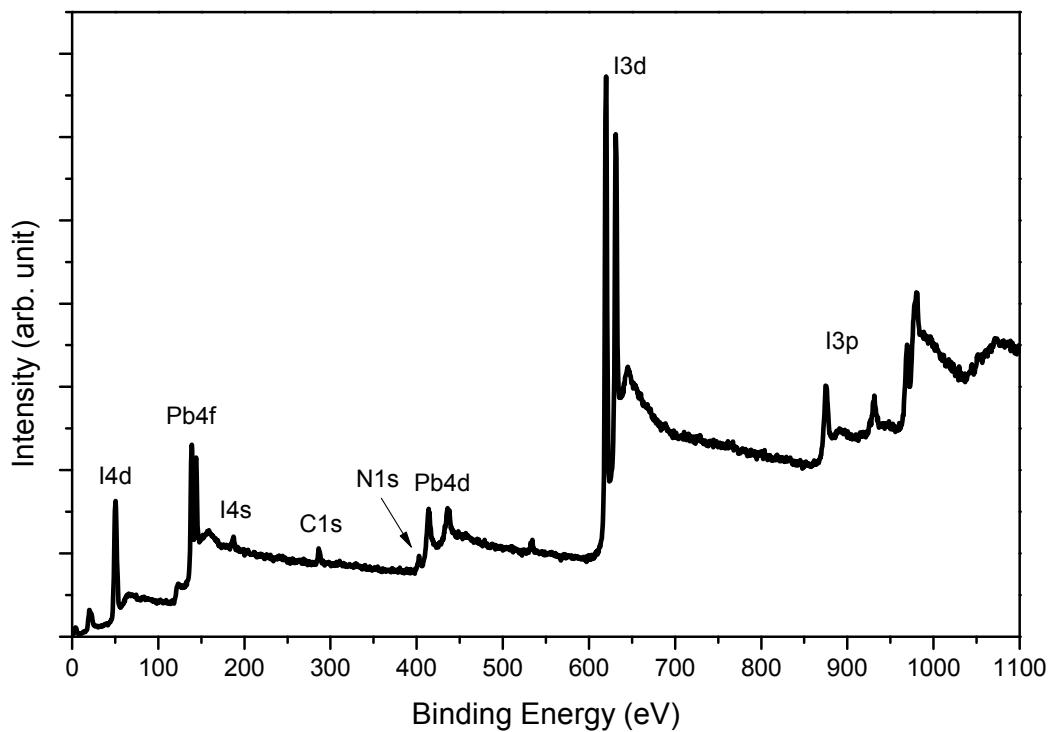


Figure S2. X-ray photoemission spectrum of a 200-nm-thick MAPbI_3 film. The stoichiometric composition of elements was estimated from peak heights to be $\text{C} : \text{N} : \text{Pb} : \text{I} \sim 1 : 0.3 : 1 : 2.5$. The lead and iodide ratio are consistent with the stoichiometry of the material, while the deviation of the nitrogen ratio might come from environmental contaminations.

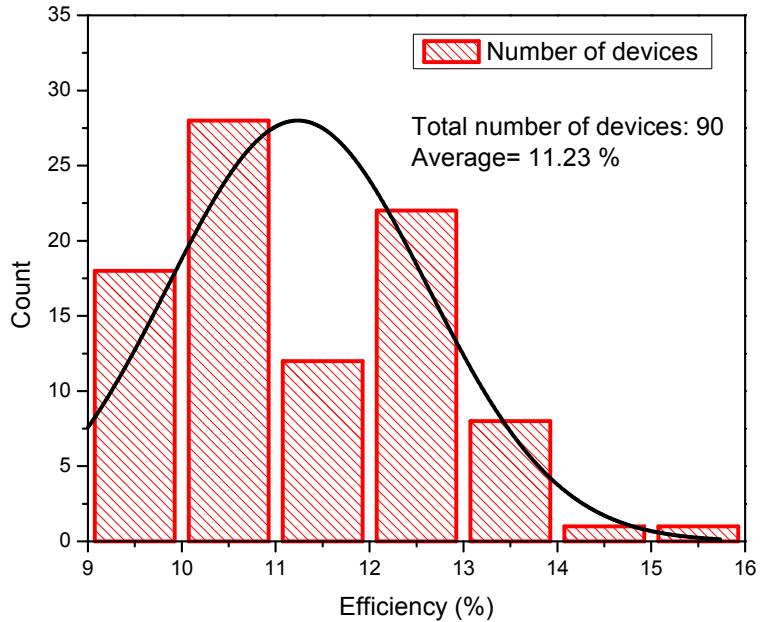


Figure S3. ITO/PEDOT:PSS/MAPbI₃/PC₆₁BM/Ca/Al solar cell device statistics

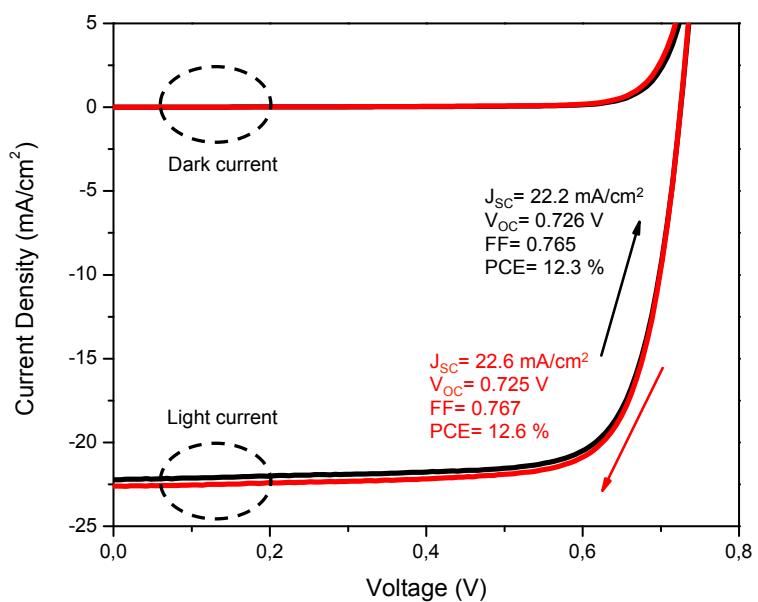


Figure S4. Typical current–voltage characteristics of a typical ITO/PEDOT:PSS/MAPbI₃/PC₆₁BM/Ca/Al solar cell. The light current was measured under AM 1.5G condition.

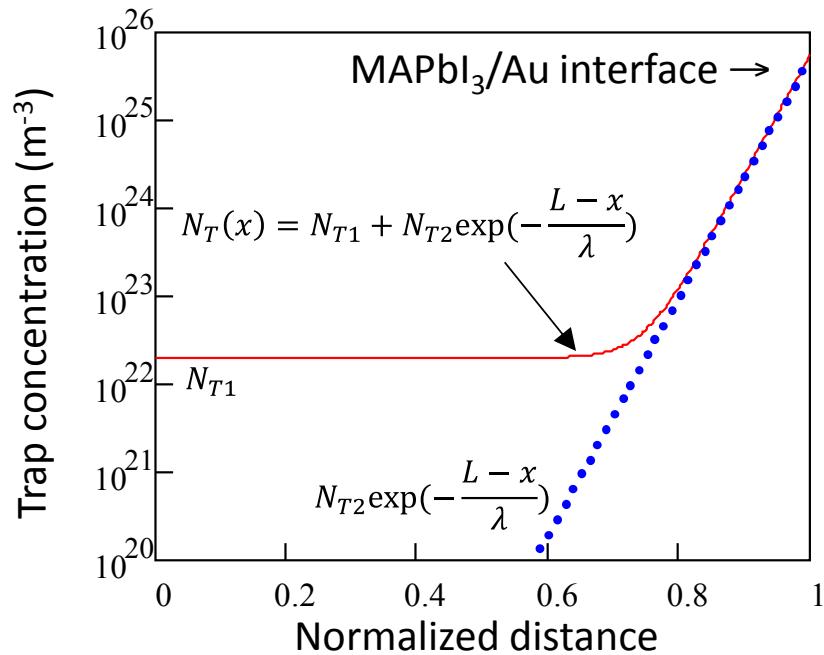


Figure S5. Trap concentration versus normalized distance according Eq.(3), illustrating the impact of the volume traps (concentration $N_{T1} = 2 \cdot 10^{22} \text{ m}^{-3}$) and the interface traps (maximum value at $x = t$: $N_{T2} = 6 \cdot 10^{25} \text{ m}^{-3}$). $\lambda = 6.5 \text{ nm}$.

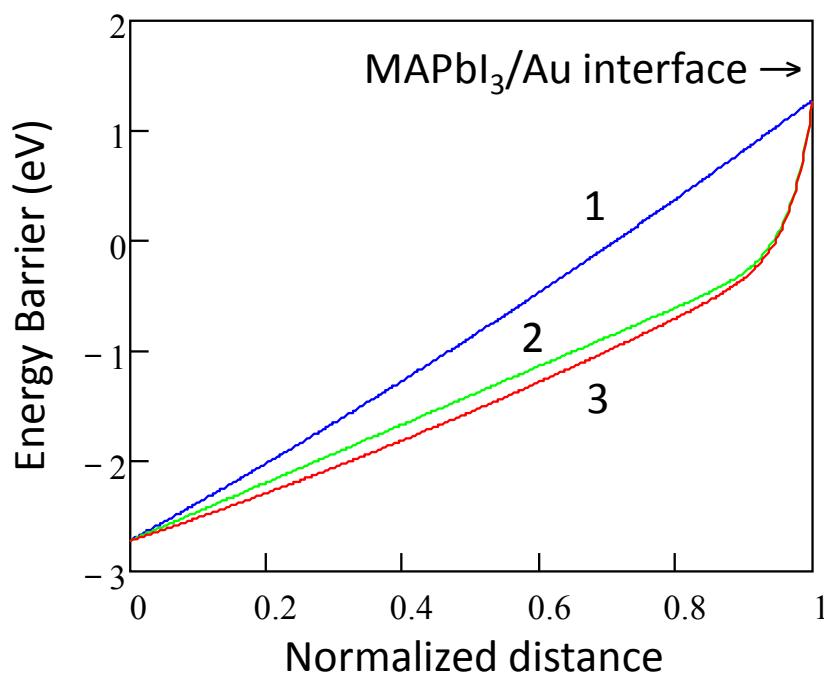


Figure S6. Energy barrier according Eq. (7) 1 with volume traps only ($N_{T1} = 5 \cdot 10^{22} \text{ m}^{-3}$); 2 with interface traps only ($N_{T2} = 6 \cdot 10^{25} \text{ m}^{-3}$, $\lambda = 6.5 \text{ nm}$); 3 with both.

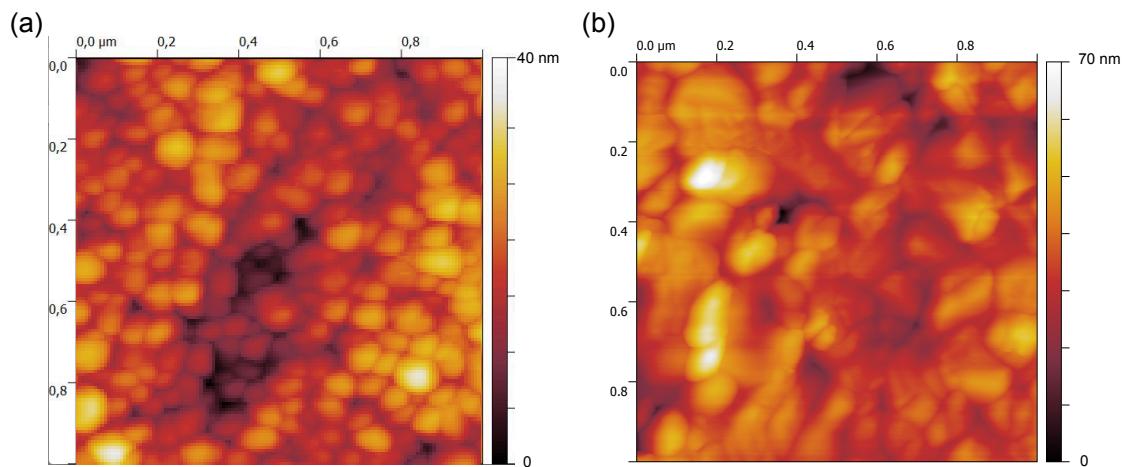


Figure S7. AFM topography of MAPbI_3 film. (a) Film thickness 450 nm. (b) Film thickness 200 nm.

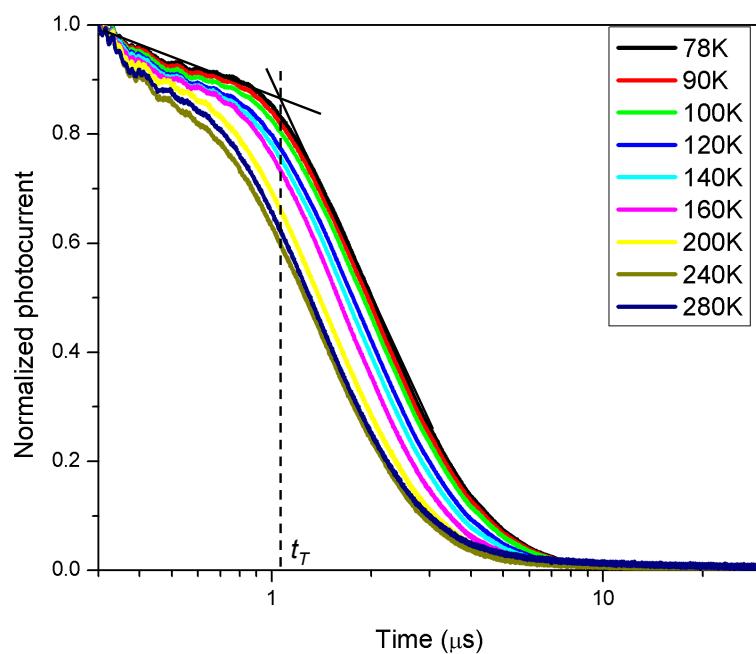


Figure S8. Temperature dependent time of flight photocurrent of ITO/PEDOT:PSS/ $\text{MAPbI}_3/\text{PC}_{61}\text{BM}/\text{Au}$ at -3 V applied bias. The transit time t_T is determined by the intercept between the two slopes on the current patterns.